



MOHR Test and Measurement LLC

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LETTER OF VOLATILITY

Part Number: CT100, CT100HF, CT100S, CT100B
Description: Automated Metallic TDR Cable Tester / Cable Analyzer
Manufacturer: MOHR Test and Measurement LLC
Revision: 2.16.18 (6/26/2019)

Table 1 -- Volatile Memory

Type	Size	User Accessible/ System Accessible ¹	Battery Backup?	Purpose	Method of Clearing ²
SDRAM	512 Mbit	No/Yes	No	System Memory	Cycle Power
MCU SRAM 1	32 Kbit	No/Yes	No	MCU Memory	Cycle Power
MCU SRAM 2	16 Kbit	No/Yes	No	MCU Memory	Cycle Power
FPGA Ram 1	65 Kbit	No/Yes	No	FPGA Memory	Cycle Power
FPGA Ram 2	65 Kbit	No/Yes	No	FPGA Memory	Cycle Power
CPU SRAM	2 Mbit	No/Yes	No	System Memory	Cycle Power
RTC Flash	512 bit	No/Yes	Yes	Stores Date & Time	Software Set / Reset

Table 2 -- Non-Volatile Memory

Type	Size	User Accessible/ System Accessible	Battery Backup?	Purpose	Method of Clearing
SD-Card	16 GBits	Yes/Yes	No	Store user and application data.	All user data can be purged in software. ³
Flash drive	256 MBits	No/No	No	Instrument Initialization	None available to user.
MCU Flash 1	256 Kbit	No/No	No	MCU Program Store	None available to user.
MCU Flash 2	512 Kbit	No/No	No	MCU Program Store	None available to user.

¹ Items are designated **No** if hardware changes or a unique software tool from MOHR is required to read or modify contents.

² The designation **None available to user** indicates that the ability to clear the memory is not available during normal operation.

³ Saved Custom Cable Types, Cable Records, and User Configurations can be deleted in the Library menu. Network Connections can be deleted in the Connections menu. These actions clear the instrument of user data. Note that deletion of user data may leave remnant data that in some instances could lead to regulatory compliance failure. *Therefore, in the event of real or perceived security compromise, the memory device should be removed by the operator for appropriate destruction to ensure appropriate security protocols have been satisfied, and a replacement card inserted. Replacement cards are available from MOHR.*

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(Table 2 continued)

Type	Size	User Accessible/ System Accessible	Battery Backup?	Purpose	Method of Clearing
MCU EEPROM 2	16 Kbit	No/No	No	Not used	None available to user.
FPGA Flash 1	4 Mbit	No/No	No	FPGA Program Store	None available to user.
FPGA Flash 2	4 Mbit	No/No	No	FPGA Program Store	None available to user.
I2C Flash	4 Kbit	No/No	No	Not used	None available to user.

Media Storage

None

Terms and Definitions

User Accessible

User accessible memory allows the user to directly write or modify the contents of the memory during normal instrument operation.

System Accessible

System accessible memory does not allow the user to access or modify the memory during normal instrument operation, however, may be accessed or modified by background processes.

Cycle Power

Cycling power is the process of completely removing power from the device and its components. This includes unplugging the device from any power source.

Volatile Memory

Volatile memory requires power to maintain the stored information. When power is removed from this memory device, its contents are lost.

Non -Volatile Memory

Non -volatile memory retains its contents when power is removed.

Media Storage

Media Storage is any memory device that can be removed and replaced by the user during normal operation.